
**Cards and security devices for
personal identification — Test
methods —**

Part 6:
Contactless proximity objects

*Cartes et dispositifs de sécurité pour l'identification personnelle —
Méthodes d'essai —*

Partie 6: Objets sans contact de proximité





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ISO copyright office
CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier; Geneva
Phone: +41 22 749 01 11
Email: copyright@iso.org
Website: www.iso.org

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Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see www.iso.org/iso/foreword.html.

This document was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology, SC 17, Cards and security devices for personal identification*.

This fourth edition cancels and replaces the third edition (ISO/IEC 10373-6:2016), which has been technically revised. It also incorporates the Amendment ISO/IEC 10373-6:2016/Amd.3:2018.

The main changes compared to the previous edition are as follows:

- enhancement of test methods for PCD load modulation reception and PICC transmission including introduction of Active Reference PICC and PICC amplitude and phase drift analysis tool;
- introduction of PICC Type A Frame Delay Time (FDT) determination method;
- extension of frame with error correction test methods.

A list of all the parts in the ISO/IEC 10373 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Cards and security devices for personal identification — Test methods —

Part 6: Contactless proximity objects

1 Scope

The ISO/IEC 10373 series defines test methods for characteristics of identification cards according to the definition given in ISO/IEC 7810. Each test method is cross-referenced to one or more base standards, which can be ISO/IEC 7810 or one or more of the supplementary standards that define the information storage technologies employed in identification card applications.

NOTE 1 Criteria for acceptability do not form part of the ISO/IEC 10373 series, but can be found in the International Standards mentioned above.

This document defines test methods which are specific to proximity cards and objects, proximity coupling devices and proximity extended devices, defined in ISO/IEC 14443-1, ISO/IEC 14443-2, ISO/IEC 14443-3 and ISO/IEC 14443-4.

NOTE 2 Test methods defined in this document are intended to be performed separately. A given proximity card or object, proximity coupling device or proximity extended device, is not required to pass through all the tests sequentially.

ISO/IEC 10373-1 defines test methods which are common to one or more integrated circuit card technologies and other parts in the ISO/IEC 10373 series deal with other technology-specific tests.

The conformance test plan defined in [Annex O](#) specifies the list of tests applicable for each part of the ISO/IEC 14443 series.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/IEC 7810, *Identification cards — Physical characteristics*

ISO/IEC 14443-1:2018, *Cards and security devices for personal identification — Contactless proximity objects — Part 1: Physical characteristics*

ISO/IEC 14443-2:2020, *Cards and security devices for personal identification — Contactless proximity objects — Part 2: Radio frequency power and signal interface*

ISO/IEC 14443-3:2018, *Cards and security devices for personal identification — Contactless proximity objects — Part 3: Initialization and anticollision*

ISO/IEC 14443-4:2018, *Cards and security devices for personal identification — Contactless proximity objects — Part 4: Transmission protocol*